# Misclassification cost-sensitive fault prediction models

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#### **ABSTRACT**

Traditionally, software fault prediction models are built by assuming a uniform misclassification cost. In other words, cost implications of misclassifying a faulty module as fault free are assumed to be the same as the cost implications of misclassifying a fault free module as faulty. In reality, these two types of misclassification costs are rarely equal. They are project-specific, reflecting the characteristics of the domain in which the program operates. In this paper, using project information from a public repository, we analyze the benefits of techniques which incorporate misclassification costs in the development of software fault prediction models. We find that cost-sensitive learning does not provide operational points which outperform cost-insensitive classifiers. However, an advantage of cost-sensitive modeling is the explicit choice of the operational threshold appropriate for the cost differential.

## **Categories and Subject Descriptors**

H.4 [Information Systems Applications]: Miscellaneous; D.2.8 [Software Engineering]: Metrics—complexity measures, performance measures

#### **General Terms**

Design, Experimentation, Performance

#### **Keywords**

Fault prediction, Machine learning, Misclassification cost, Costsensitive

## 1. INTRODUCTION

#### 1.1 Fault Prediction Models

Research studying the detection of software modules which are likely to contain faults has been ongoing for a long time. The faulty information not only points to the need for increased quality monitoring during the development but also provides important advice to assign verification and validation activities. Various studies show that software companies spend 50% to 80% of their software development efforts on testing [34]. The identification of faulty modules

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might have a significant cost-saving impact on software development

A wide range of software metrics have been proposed for collection and used to identify modules which may contain faults [16]. Metrics describing software requirements (i.e. requirement documents) achieved notable success in predicting faulty modules [21, 35, 19]. Design metrics, either collected from design documents or reverse engineered from code, have proved their utility for fault prediction [42, 45]. Static code metrics, such as Halstead complexity [18] and various code size metrics, have also proven their effectiveness in many studies [36, 40, 26, 17, 7].

Metrics related to developer social networks have recently received significant attention. Weyuker, Ostrand, and Bell [47] found that the addition of developer information improves the accuracy of fault prediction models. Li et al. analyzed 139 metrics collected from software product, development, deployment, usage, software and hardware configurations in OpenBSD [31]. They found that the number of messages to the technical discussion mailing list during the development period is the best predictor of the number of field faults. Nagappan et al. [41] collected 8 organizational structure metrics which relate binary files to the social networks, i.e., the number of engineers, the number of ex-engineers, edit frequency of source code, and organization intersection factors to predict faults. They compared this model with models which use five traditional groups of metrics such as code churn, code complexity, code coverage, dependency, and pre-release faults. They report that metrics from organizational structure are better predictors of software faults than the other five groups of metrics. The use of organizational structure complexity metrics appears to hold a significant promise for fault prediction. Unfortunately, no organizational complexity metrics are available in the data sets we analyze in this paper.

## 1.2 Importance of Cost

The "traditional" software fault prediction models, some referenced above and others mentioned in Section 5, typically assume uniform misclassification cost. In other words, this models suppose that the cost implications of wrongly predicting a faulty module as fault free one is the same as the cost of indicating that a fault free module may contain faults. In reality, the cost implications of these two types of misclassification are seldom equal in the real world. In high risk software projects, for example, safety-related spacecraft navigation instruments, the cost of missing a faulty module may have extreme consequence associated with a loss of the entire mission. Therefore, in such projects significant resources are typically available for identifying and eradicating all faults because the cost of losing a mission is much higher. On the other hand, in low risk

projects which aim to occupy a new market niche, time to market pressure may imply that only a minimal number of faulty modules can be analyzed. The cost of analyzing any significant number of misclassified fault free modules is, therefore, unacceptable.

What makes the prediction of faulty modules a challenge is the reality that they usually form a minority class compared to fault free modules. The faulty and non-faulty classes are typically imbalanced. Therefore, in order to develop models which find more faults, one would expect that explicit placement of a cost premium for fault identification will increase the accuracy of such models. This expectation represents the motivation for the research described in this paper.

## 1.3 Cost in Model Evaluation

While the techniques for model development which explicitly account for misclassification cost differential have not been studied in software fault prediction modeling, there have been attempts to include cost factors into model evaluation. *F-measure*, for example, offers a technique to account for the cost factor [20] when comparing different models. Khoshgoftaar and Allen [27] proposed the use of prior probabilities of misclassification to select classifiers which offer the most appropriate performance. In [28] they compare the return-on-investment in a large legacy telecommunication system when V&V activities are applied to software modules selected by a fault prediction model vs. at random. Cost has been considered in test case selection for regression testing too [13, 14].

There is a steady trend in fault prediction modeling literature recommending model evaluation with lift charts [20], sometimes called Alberg diagrams [42, 44]. Lift is a measure of the effectiveness of a classifier in the detection of faulty modules. It calculates the ratio of correctly identified faulty modules with and without the predictive model. Lift chart is especially useful when the project has resources to apply verification activities to a limited number of modules. Cost effectiveness measure described by Arisholm  $\it et al.$  [2] can account for the nonuniform cost of module-level  $\it V\&V$ . As opposed to these approaches, our goal is to analyze the benefits of incorporating project specific misclassification costs in the development of software fault prediction models, as opposed to their evaluation.

The remainder of this paper is organized as follows. Section 2 introduces our method of cost-sensitive modeling and our experimental design. Section 3 presents our experimental result and analysis. Section 4 offers a short overview of related work. Section 5 concludes the paper.

#### 2. COST-SENSITIVE MODELING

In spite of the importance of misclassification cost in software fault prediction modeling, most classifiers simply do not allow the incorporation of cost into the modeling process. Instead they are typically designed to increase the overall prediction accuracy (or decrease the overall error rate) assuming that all misclassifications have the same cost.

In this section, we introduce a method to incorporate different misclassification costs into software fault prediction modeling. In these cost-sensitive models, the goal will be to minimize the overall misclassification cost. This is quite different from the cost-insensitive models. First, we discuss the confusion matrix and the corresponding measurements used in this study. Then we explain our costsensitive classification methods. Finally, we explain experimental

	actual faulty	actual non-faulty
predict faulty	TP	FP
predict non-faulty	FN	TN

yRecall = yPD =	$\frac{TP}{TP+FN}$
yPF =	$\frac{FP}{FP+TN}$
yPrecision =	$\frac{TP}{FP+TP}$
nRecall == nPD =	$\frac{TN}{FP+TN}$
nPF =	$\frac{FN}{TP+FN}$
nPrecision =	$\frac{IN}{TN+FN}$

**Figure 1: Confusion Matrix** 

design used to analyze the results.

#### 2.1 Confusion Matrix

Figure 1 shows a confusion matrix. It has four categories: True positives (TP) are modules correctly classified as faulty modules. False positives (FP) refer to fault-free modules incorrectly labeled as faulty. True negatives (TN) correspond to correctly classified fault-free modules. Finally, false negatives (FN) refer to faulty modules incorrectly classified as fault-free. In this study, we will use recall, precision, and PF to evaluate prediction models. Recall represents the probability of detection (PD) of faulty (or non-faulty) modules. In this study, recall of faulty modules is denoted as yRecall, recall of non-faulty modules is nRecall. Precision is the proportion of the correctly predicted (faulty or non-faulty) modules inside each prediction class: precision for faulty modules is denoted yPrecision, for non-faulty modules nPrecision. PF represents the probability of false alarms: PF for faulty modules is denoted as yPF, for non-faulty modules nPF.

Receiver Operating Characteristic (ROC) curve is a plot of the probability of detection  $(recall\ or\ PD)$  as a function of the probability of false alarm (PF) across all threshold settings. An ROC curve provides an intuitive way to evaluate the classification performance of software fault prediction models. Many classifiers allow users to define and adjust threshold parameters in order to generate an appropriate performance [48]. The Area Under the ROC Curve (AUC) is a numeric performance evaluation measure directly associated with an ROC curve. In this study, we will utilize ROC and AUC for model evaluation.

Boxplot diagrams, also known as box and whisker diagrams, graphically depict numerical data distributions using the five first order statistics: the smallest observation, lower quartile(Q1), median, upper quartile(Q3), and the largest observation. The box is constructed based on the interquartile range(IQR) from Q1 to Q3. The line inside the box depicts the median which follows the central tendency. Outliers may be indicated as bubbles (or squares) lying below/above 1.5\*IQR. The whiskers indicate the smallest and the largest observations which are not outliers.

#### 2.2 Modeling Algorithms

In this study, the term cost always stands for the  $misclassification\ cost$ . Figure 2 shows a cost matrix similar to the confusion matrix shown in Figure 1. The cost matrix emphasizes the implications of misclassification. For this reason, the costs of correct classifications are 0. If a fault free module is misclassified as faulty (FP), additional V&V activity imply additional expenditure. In Figure 1, this

	actual faulty	actual non-faulty
predict faulty	0 (TP)	1(FP)
predict non-faulty	5(FN)	0(TN)

Figure 2: Cost matrix, an example

misclassification cost is assumed to be a factor 1. If a faulty module is misclassified as fault free (FN), the cost indicates the potential for future damages. In Figure 1, it is assumed to be 5 times more expensive than FP.

The MetaCost method introduced by Domingos [11] makes classifiers cost-sensitive. Let i, j denote two classes, m denotes a module. The probability P(j|m) stands for the probability that m belongs to class j. C(i,j) denotes the costs denoted in the cost matrix. MetaCost tries to minimize the misclassification cost by using Bayes optimal prediction:

$$R(i|m) = \sum_{j} P(j|m)C(i,j)$$
 (1)

The misclassification  $\cos R(i|m)$  is the expected  $\cos$  of predicting that module m belongs to class i. MetaCost aims to achieve the lowest possible overall misclassification  $\cos$  over all modules by wrapping a procedure described in Equation 1 to a regular costinsensitive classifier [11]. MetaCost works as follows [11]:

- First, bootstrap the training subset to form a sample; run the base cost-insensitive classifier on the bootstrapped sample. This procedure is repeated multiple times.
- Estimate class' probability P(j|m) for each module m, across all bootstraped samples.
- Given the known cost matrix, C(i,j), using Equation 1 relabel each module with the estimated optimal class in order to minimize the overall misclassification cost, R(i|m). This process results in an optimal model.
- Apply the model developed accordingly to the test subset samples.

Observe that with different cost matrices, the last two steps need to be adjusted accordingly. According to Domingos, "MetaCost treats the underlying classifier as a blackbox, requiring no knowledge of its functioning or change to it" [11]. Weka offers MetaCost procedure proposed by Domingos as a wrapper to any supported classifier.

## 2.3 Design of Experiments

The 13 data sets listed in Table 1 come from the NASA Metrics Data Program (MDP) repository [1]. The projects offer module metrics associated with NASA Space Shuttle software. JM1 and KC1 have 21 attributes that can be used as predictor variables, MC1 and PC5 have 39, while the other data sets have 40.

We do not know the cost matrix appropriate for each project. In order to investigate the effect of cost-sensitive classification in software fault prediction models, we assign 11 different cost matrices to all projects shown in Table 2. In Table 2, the cost of TP and TN are zero. We use  $cost\_ratio$  to denote a cost matrix which is shown in Table 2 as the third column. For example, in the first row, the ratio between FN and FP is  $\frac{1}{75}$ . The first five cost matrices represent for low risk projects and the last five cost matrices stand for the high risk projects.

The 11 cost ratios from Table 2 are run on each classifier over each data set. We use standard 10 way cross-validation (CV) method in this study. CV is the statistical practice of randomized partitioning of a data set into two parts: one part of data is used as training and the remaining part of data is left as testing subset. In this study, 50% of the data is used for training and the other 50% is used for testing. The partition is randomized 10 times and run 20 times on each data set to get a better understanding of variance.

In experiments, we use five classifiers from Weka which consistently demonstrate good performance [20, 23, 24, 21]: random forest (rf), boosting (bst), logistic (log), naiveBayes (nb), and bagging (bag). The measures evaluated in this study are precision (yPrecision and nPrecision) and recall (yRecall and nRecall). Using 13 data sets, 11 different cost matrices, 5 machine learners, and 20 cross validation runs, in total, our experiments resulted in 14, 300 runs.

## 3. ANALYSIS OF EXPERIMENTS

For each classifier – data set combination, we generate two boxplot diagrams, which depict precision and recall for faulty and for non-faulty modules. In total, there are 13\*5\*2=130 such diagrams. Understandably, we cannot describe all our observations in a paper, and neither would it be very interesting. However, we observed the following trends: logistic and boosting classifiers offer very similar performance characteristics; bagging is similar to random forests; NaiveBayes is quite different as the impact of cost, measured by precision or recall, seems to have a minor, if any, impact. Therefore, we use logistic and bagging classifiers as examples to illustrate observed results. Figure 3 depicts boxplot diagrams for precision and precision

From Figure 3, we can observe the clear increase of recall with the decrease of precision in the detection of faulty modules when  $cost\_ratio$  varies from 1/75 to 75. However, the rate of increase depends on the classifier. As expected, when identifying fault free modules, recall decreases as precision increases.

Table 3 shows the median precision, recall, and PF for faulty and fault free classes for 5 classifiers on CM1 and JM1 two data sets. The performance indices for  $cost\_ratio$  of 1/25, 1/5, 5, and 25 are omitted as they follow the overall performance trends. In low risk situations  $(cost\_ratio < 1)$  misclassifying fault free modules is more expensive than misclassifying faulty ones. yRecall is, therefore, very low. For example, in CM1 project from 0.25 to 0.26 using naive bayes down to 0 with bagging and random forest. yPrecision is not good either. On the contrary, nRecall and nPrecision are all quite high, greater than 0.80 with some even as high as 1. This is not difficult to explain for field use data. When there are limited resources to verify modules in a software project, the cheapest choice is to check as few modules as possible. The behavior of bagging and random forest in these circumstances mimics trivial classifiers by classifying every module as fault free.

In high risk projects ( $cost\_ratio > 1$ ) misclassifying a faulty module as fault free is undesirable. The data sets used in this study fall into this category, i.e., in most cases the models should identify as many faults as possible. The good news is that when we increase  $cost\_ratio$  from 1 to 75, yRecall increases, although the rate of increase depends on the algorithm. The bad news, although not unexpected, is the decrease of yPrecision which implies needless analysis of a large number fault free modules (false positives). The

Table 1: Datasets used in this study

Data	mod.#	% faulty	project description	lang.
JM1	10,878	19.3%	Real time predictive ground system	С
MC1	9466	0.64%	Combustion experiment of a space shuttle	(C)C++
PC2	5589	0.42%	Dynamic simulator for attitude control systems	С
PC5	17,186	3.00%	Safety enhancement system	C++
PC1	1109	6.59%	Flight software from an earth orbiting satellite	C
PC3	1563	10.43%	Flight software for earth orbiting satellite	С
PC4	1458	12.24%	Flight software for earth orbiting satellite	С
CM1	505	16.04%	Spacecraft instrument	C
MW1	403	6.7%	Zero gravity experiment related to combustion	C
KC1	2109	13.9%	Storage management for ground data	C++
KC3	458	6.3%	Storage management for ground data	Java
KC4	125	48%	Ground-based subscription server	Perl
MC2	161	32.30%	Video guidance system	C++

Table 2: Eleven different cost matrices assigned to 13 projects in this experiment.

cost of FN	cost of FP	denoted as cost_ratio	risk type	note
1	75	1/75	low	
1	50	1/50	low	
1	25	1/25	low	lower cost to misclassifying faulty modules
1	10	1/10	low	
1	5	1/5	low	
1	1	1		equal cost to both classes
5	1	5	high	
10	1	10	high	
25	1	25	high	higher cost to misclassifying faulty modules
50	1	50	high	
75	1	75	high	

optimal goal is to have high recall and precision at the same time, but that seems impossible to achieve by varying  $cost\_ratio$  only. For example, in JM1 project when  $cost\_ratio$  is greater than 50, yRecall increases to 1 (using logistic and boosting) while nRecall decreases to 0. This, again, reflects the result of a trivial classifier which tags every module as faulty.

Figure 3 and Table 3 lead us towards the following observations:

- Faulty modules are the minority class. Different cost parameters indicate a compromise between *yPrecision* and *yRecall*. Nevertheless, some classifiers offer better tradeoffs between the two evaluation parameters.
- Boosting, bagging and random forest algorithms consistently reach yRecal rates close to 1 at high cost ratios, with precision slightly above 0.2.
- No matter what the cost\_ratio is, nPrecision and nRecall
  for identifying fault free modules are very high, reflecting the
  fact that this is the majority class.
- NaiveBayes is quite different from the other four classifiers. It's performance indices (precision, recall, PF) are rather constant regardless of the cost.

We also want to acknowledge the high variance of yPrecision in Figure 3 at  $cost\_ratio = 1/5$ . Essentially, the precision in identifying faulty modules varies from 0 to close to 1. We noticed similar spikes in precision variance in a few other experiments. For example, random forest on JM1 project at  $cost\_ratio = 1/25$ , boosting on KC3 data with  $cost\_ratio$  between 1/75 and 1/5, bagging on PC1 data with  $cost\_ratio = 1$  all report very high variance for precision. Similarly, when the goal is to identify fault free modules, nPrecision at high  $cost\_ratio$  may have a big variance too:

NaiveBayes on MC1 with  $cost\_ratio$ =75, random forest on MC2 at  $cost\_ratio$  50 and 75, logistic with JM1 with  $cost\_ratio$  between 50 and 75. These observations point that future research in software fault prediction modeling must take such variances into account when recommending best practices. With such unreliable performance, it is difficult to trust prediction results. Menzies et al. indicate that precision is not a good evaluation metric for fault prediction models [37]. The good news is that recall does not appear to suffer from big variances through all the experiments in this study. Therefore, recall should be relied upon when evaluating the performance of software fault prediction models.

## 3.1 Statistical significance

We further conducted a statistical test procedure to compare yRecall across 11 different cost matrices for each classifier with each data set, using Demsar's test [9, 20]. Our hypotheses are:  $H_0$ : There is no difference in the performance among 11 different cost matrices for a classifier on a specific data set evaluated using yRecall. vs.

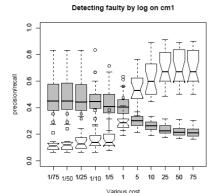
 $H_{\alpha}$ : At least two different cost matrices have significantly different performance for a learner on a specific data set evaluated by using yRecall.

Using 95% confidence interval to evaluate the significance of test, five classifiers and 13 data sets, we conducted Demsar's test 65 times. Amongst the 65 tests, only two accepted  $H_0$  and rejected  $H_{\alpha}$ : naive bayes on JM1 and MW1. In other 63 tests, the hypothesis  $H_0$  is rejected and  $H_{\alpha}$  is accepted. The yRecall based performance ranks prefer higher  $cost\_ratios$ .

Statistically significant differences in performance when all 11 cost

Table 3: Median of precision and recall for 5 classifiers on CM1 and JM1 data set. yPrecision and yRecall stand for precision and recall for faulty modules; nPrecision and nRecall are corresponding precision and recall rates for identification of fault free modules.

log	dataset	learner	cost_ratio	yPF	yPrecision	yRecall	nPF	nPrecision	nRecall
log					1	l			
					1	l			
cml         log         10         0.34         0.24         0.67         0.33         0.9         0.52           log         75         0.49         0.21         0.67         0.33         0.9         0.51           bst         1/75         0.49         0.21         0.67         0.33         0.9         0.51           bst         1/75         0.49         0.21         0.67         0.33         0.9         0.51           bst         1/10         0.01         0.41         0.03         0.95         0.95         0.84         1           bst         1/10         0.01         0.41         0.03         0.99         0.84         1           bst         10         0.38         0.22         0.9         0.3         0.91         0.62           cml         bst         75         0.64         0.22         0.9         0.1         0.95         0.36           bag         1/75         0         0         0         1         0.84         1         0.95         0.36           cml         bag         1/70         0         0         0         1         0.84         1         0         0					l .	ı			
Cml   Jog   50   0.48   0.21   0.67   0.33   0.9   0.52					l .	ı			
	cm1				l .	!			
bst   175   0   0.54   0.05   0.95   0.84   1     bst   170   0.01   0.59   0.04   0.96   0.84   1     bst   1710   0.01   0.41   0.03   0.98   0.84   0.99     bst   1   0.03   0.43   0.13   0.87   0.85   0.97     bst   10   0.38   0.25   0.7   0.3   0.91   0.62     cm1   bst   50   0.63   0.21   0.88   0.13   0.94   0.37     bst   75   0.64   0.22   0.9   0.1   0.95   0.36     bag   1750   0   0   0   1   0.84   1     bag   1750   0   0   0   1   0.84   1     bag   1750   0   0   0   1   0.84   1     bag   170   0.33   0.26   0.63   0.37   0.91   0.67     bag   10   0.33   0.26   0.63   0.37   0.91   0.67     bag   10   0.33   0.26   0.63   0.37   0.91   0.67     bag   75   0.79   0.19   0.98   0.02   0.98   0.21     ff   1750   0   0   0   1   0.84   1     ff   1760   0   0   0   1   0.84   1     ff   1775   0   0   0   0   1   0.84   1     ff   175   0.62   0.22   0.94   0.06   0.97   0.38     cm1   ff   50   0.53   0.23   0.84   0.16   0.94   0.47     ff   75   0.62   0.22   0.94   0.06   0.97   0.38     nb   170   0.08   0.36   0.25   0.75   0.86   0.92     nb   175   0.08   0.36   0.25   0.75   0.86   0.92     nb   1   0.09   0.34   0.27   0.73   0.87   0.99     nb   1   0.09   0.34   0.27   0.73   0.87   0.99     nb   1   0.09   0.81   0.10   0.99   0.81   1     log   175   0   0.77   0.01   0.99   0.81   1     log   175   0   0.88   0.01   0.99   0.81   1     log   175   0   0.88   0.01   0.99   0.81   1     log   175   0   0.88   0.01   0.99   0.81   1     log   175   0   0   0   0   1   0.84   0.98     jm1   bst   50   1   0.19   1   0   0   0   0     ff   175   0   0   0   0   0   1   0.81   1     bst   170   0   0.88   0.01   0.99   0.81   1     log   175   0   0   0   0   0   0   0   0     ff   176   0   0   0   0   0   0   0   0     ff   176   0   0   0	CIIII				1	l			
bst   1/50   0.01   0.59   0.04   0.96   0.84   1   0.99   0.81   1/10   0.01   0.41   0.03   0.98   0.84   0.99   0.84   0.99   0.81   1   0.03   0.43   0.13   0.87   0.85   0.97   0.85   0.97   0.85   0.97   0.85   0.97   0.85   0.97   0.85   0.97   0.85   0.97   0.95   0.36   0.95   0.98   0.11   0.95   0.36   0.95   0.36   0.94   0.37   0.95   0.36   0.94   0.37   0.95   0.36   0.94   0.98   0.15   0.96   0.94   0.84   1   0.98   0.98   0.15   0.96   0.94   0.84   1   0.98									
bst   1/10   0.01   0.41   0.03   0.98   0.84   0.99   0.81   0.81   0.05   0.62   0.77   0.38   0.97   0.85   0.97   0.85   0.97   0.85   0.97   0.36   0.99   0.11   0.85   0.97   0.36   0.21   0.88   0.13   0.94   0.37   0.85   0.96   0.36   0.21   0.88   0.13   0.94   0.37   0.85   0.36   0.25   0.99   0.11   0.95   0.36   0.38   1   0.02   0.35   0.06   0.94   0.84   1   0.98   0.36   0.36   0.37   0.91   0.67   0.36   0.36   0.36   0.37   0.91   0.67   0.36   0.36   0.36   0.37   0.91   0.67   0.36   0.37   0.91   0.67   0.36   0.36   0.37   0.91   0.67   0.36   0.37   0.91   0.67   0.36   0.36   0.37   0.91   0.67   0.36   0.37   0.91   0.67   0.37   0.19   0.98   0.02   0.98   0.21   0.36   0.36   0.36   0.02   0.98   0.21   0.36   0.36   0.36   0.02   0.98   0.21   0.36   0.									
cm1 bst					l .	ı			
cm1         bst         50         0.63         0.21         0.88         0.13         0.94         0.37           bag         1/75         0         0         0         0         1         0.84         1           bag         1/10         0         0         0         1         0.84         1           bag         1/10         0         0         0         1         0.84         1           bag         1         0.02         0.35         0.06         0.94         0.84         1           cm1         bag         10         0.33         0.26         0.63         0.37         0.91         0.67           cm1         bag         50         0.71         0.2         0.93         0.07         0.96         0.29           bag         75         0.79         0.19         0.98         0.02         0.98         0.21           rf         1/75         0         0         0         1         0.84         1           rf         1/10         0         0         0         1         0.84         1           rf         1/50 0         0.53         0.53		bst		0.03	0.43	0.13	0.87	0.85	0.97
bag		bst		0.38			0.3		0.62
bag   1/75   0   0   0   1   0.84   1   0.84   1   0.85   0.66   0.63   0.37   0.91   0.67   0.67   0.70   0.95   0.02   0.98   0.02   0.02   0.02   0.02   0.02   0.02   0.02   0.02   0.02   0.03   0.77   0.03   0.03   0.77   0.03	cm1					1			
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cm1   bag   1/10   0   0   0   0   0   0   0   0   0				l					
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cm1         bag         50         0.71         0.2         0.93         0.07         0.96         0.22           rf         1/75         0         0         0         1         0.84         1           rf         1/50         0         0         0         1         0.84         1           rf         1/10         0         0         0         1         0.84         1           rf         1/10         0         0         0         1         0.84         1           rf         1/10         0.03         0.55         0.19         0.81         0.86         0.97           rf         1         0.03         0.55         0.19         0.81         0.86         0.97           rf         1         0.03         0.55         0.19         0.81         0.86         0.92           rf         1         0.03         0.55         0.19         0.81         0.86         0.92           rf         75         0.08         0.36         0.25         0.75         0.86         0.92           nb         1/10         0.08         0.36         0.25         0.75         0.86				l					
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cm1         rf         10         0.17         0.33         0.47         0.54         0.89         0.83           rf         50         0.53         0.23         0.84         0.16         0.94         0.47           nb         1/75         0.62         0.22         0.94         0.06         0.97         0.38           nb         1/50         0.08         0.36         0.25         0.75         0.86         0.92           nb         1/10         0.08         0.36         0.25         0.75         0.86         0.92           nb         1/10         0.08         0.36         0.26         0.74         0.87         0.92           nb         1/10         0.08         0.36         0.26         0.75         0.86         0.92           nb         1/10         0.09         0.34         0.27         0.73         0.87         0.91           cm1         nb         50         0.11         0.32         0.3         0.71         0.87         0.99           cm1         nb         50         0.11         0.32         0.3         0.7         0.88         0.89           log         1/50 <t< td=""><td></td><td></td><td></td><td>0</td><td></td><td>0</td><td></td><td></td><td></td></t<>				0		0			
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log		log	1/75	0	0.77	0.01	0.99	0.81	1
log		log	1/50	0	0.76	0.01	0.99	0.81	1
Jiml   log   10   0.83   0.22   0.94   0.06   0.93   0.17					1	1			
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bag bag         1/50         0         0         0         0         1         0.81         1           bag         1/10         0         0         0         1         0.81         1           bag         1         0.04         0.51         0.19         0.81         0.83         0.96           jm1         bag         50         0.43         0.29         0.74         0.26         0.9         0.57           jm1         bag         50         0.87         0.21         0.98         0.03         0.96         0.13           bag         75         0.95         0.2         0.99         0.01         0.97         0.06           rf         1/75         0         0         0         1         0.81         1           rf         1/50         0         0         0         1         0.81         1           rf         1/10         0         0.87         0.01         1         0.81         1           rf         1/10         0         0.87         0.01         1         0.81         1           rf         1         0.05         0.53         0.22         0.78 </td <td></td> <td></td> <td></td> <td></td> <td></td> <td></td> <td></td> <td></td> <td></td>									
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rf         1/10         0         0.87         0.01         1         0.81         1           rf         1         0.05         0.53         0.22         0.78         0.84         0.95           rf         10         0.24         0.36         0.57         0.44         0.88         0.76           jm1         rf         50         0.69         0.24         0.91         0.09         0.94         0.31           rf         75         0.8         0.22         0.95         0.05         0.95         0.2           nb         1/75         0.05         0.49         0.18         0.82         0.83         0.95           nb         1/50         0.05         0.49         0.18         0.82         0.83         0.95           nb         1/10         0.05         0.49         0.19         0.81         0.83         0.95           nb         1         0.05         0.48         0.2         0.8         0.83         0.95           nb         10         0.06         0.48         0.21         0.79         0.83         0.94           jm1         nb         50         0.06         0.48			1/50						
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jm1         rf         50         0.69         0.24         0.91         0.09         0.94         0.31           rf         75         0.8         0.22         0.95         0.05         0.95         0.2           nb         1/75         0.05         0.49         0.18         0.82         0.83         0.95           nb         1/50         0.05         0.49         0.18         0.82         0.83         0.95           nb         1/10         0.05         0.49         0.19         0.81         0.83         0.95           nb         1         0.05         0.48         0.2         0.8         0.83         0.95           nb         10         0.06         0.48         0.21         0.79         0.83         0.94           jm1         nb         50         0.06         0.48         0.22         0.78         0.83         0.94			1						
rf         75         0.8         0.22         0.95         0.05         0.95         0.2           nb         1/75         0.05         0.49         0.18         0.82         0.83         0.95           nb         1/50         0.05         0.49         0.18         0.82         0.83         0.95           nb         1/10         0.05         0.49         0.19         0.81         0.83         0.95           nb         1         0.05         0.48         0.2         0.8         0.83         0.95           nb         10         0.06         0.48         0.21         0.79         0.83         0.94           jm1         nb         50         0.06         0.48         0.22         0.78         0.83         0.94						l			
nb         1/75         0.05         0.49         0.18         0.82         0.83         0.95           nb         1/50         0.05         0.49         0.18         0.82         0.83         0.95           nb         1/10         0.05         0.49         0.19         0.81         0.83         0.95           nb         1         0.05         0.48         0.2         0.8         0.83         0.95           nb         10         0.06         0.48         0.21         0.79         0.83         0.94           jm1         nb         50         0.06         0.48         0.22         0.78         0.83         0.94	jm1								
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nb         10         0.06         0.48         0.21         0.79         0.83         0.94           jm1         nb         50         0.06         0.48         0.22         0.78         0.83         0.94									
jm1   nb   50   0.06   0.48   0.22   0.78   0.83   0.94			10						
	jm1		50						



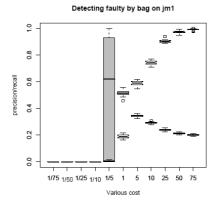


Figure 3: Boxplot diagrams depict precision and recall for identifying faulty and non-faulty modules using different  $cost\_ratio$ . Shaded rectangle stands for precision; unshaded notch stands for recall. Outliers for precision are indicated as bubbles; and outliers for recall are indicated as squares.

ratios are taken into account are not surprising. Another important question is how sensitive models are to small changes in the misclassification cost ratio. For this test, we will apply Demsar's procedure to compare the rank performance of classification models for each classifier using costs which range from 1 to 75.

Figure 4 depicts the results for random forest classifier over all the 13 projects. Any two classifiers which lay within the critical distance (CD=1.69) offer performance which cannot be interpreted as different using 95% confidence interval. Using yRecall as the performance measure, in most data sets models developed using cost ratios 50 and 75, or 1 and 5 perform similarly. Analysis of other classifiers offer similar results. For this reason, we conclude that knowing the exact misclassification cost is not as important as knowing its approximate cost range.

Using recall to evaluate the models' performance to detect faulty modules, we conclude that fault prediction generally benefits from cost-sensitive learning in high risk cases because higher recall values, which indicate higher performance ranks, are obtained by applying higher. But the bottom line question is whether similar performance could have been achieved through the traditional model development, not "burdened" by the various misclassification cost factors.

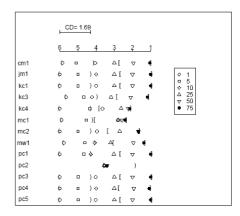


Figure 4: Demsar's rank test states that the rank performance of classifiers within the critical distance (CD=1.65) is not statistically different. Classifiers were developed using random forest algorithm and misclassification costs from 1 to 75.

## 3.2 Cost-sensitive vs. cost-ignorant

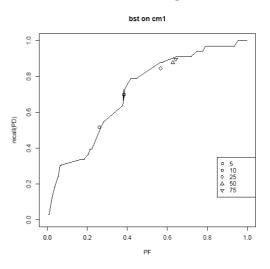


Figure 5: The ROC curve of cost-ignorant model and the median (PF, recall) points for five different  $cost\_ratio > 1$  on CM1. All models developed using boosting. Figure 5 shows the ROC curve obtained from the boosting classifier

Figure 5 shows the ROC curve obtained from the boosting classifier using the traditional cost-ignorant modeling approach on CM1 data set. In the same figure, we overlayed the five median (PF, recall) points of cost-sensitive learning with the values of  $cost_ratio > 1$  over the ROC curve. The cost sensitive models have been developed using the same boosting classifier wrapped in the MetaCost procedure [11]. We can observe that all five classifiers obtained through cost-sensitive modeling can be obtained from cost-ignorant model development by adjusting the model thresholds. The observations from this diagram are repeated for other classifiers and other data sets. Another example is shown in Figure 6.

To generalize, appropriate threshold selection in cost-ignorant models offers the models with performance equivalent to models de-

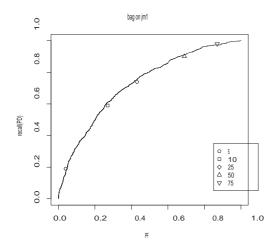


Figure 6: The ROC curve of cost-ignorant model and the median (PF, recall) points for five different  $cost\_ratio > 1$ . All models developed using bagging.

rived using cost-sensitive modeling methodology. Cost-sensitive modeling does not provide operational points which outperform "traditional" classifiers, as evaluated by recall.

The other important implication from this study is that we can use cost to choose suitable operational threshold (based on different  $cost\_ratio$ ) to control a classifier's performance. In this study, four classifiers except naive bayes provide this flexibility.

#### 3.3 Discussion

The experiments presented above provide valuable information in the quest to understand the best modeling practices for software fault prediction. The inclusion of misclassification cost ratio seems a natural choice in the software engineering domain, as in many cases the consequences of system failures far outweigh the cost of module verification activities.

The fact that the models developed using cost-sensitive modeling algorithm do not outperform the "traditional", cost-ignorant models has a two fold interpretation. The bad news is that this approach is not opening a new frontier in model performance. There is a good news, though. Cost-sensitive modeling explicitly reveals the model which minimizes the overall cost of software faults, given that one can trust the assumed misclassification cost ratio. Selecting a appropriate model for predicting faulty modules through the explicit notion of cost seems much easier for practitioners than tinkering and / or justifying one amongst many possible threshold values of the model.

In practice, exact costs are rarely known and could change as we learn more about system requirements, its design, operational environment, etc. When considering a wide range of cost ratios the resulting models differ significantly. Nevertheless, our tests indicate that changing the misclassification cost ratio from, say, 50 to 75 or 25 to 50 result in models whose performance is not significantly different. Software project managers who are likely to desire analyzing various cost situations do not need to analyze many of them, as the trends will be easy to understand.

## 3.4 Threats to Validity

We analyze three types of validity threats.

Considering internal validity, MDP data sets are generated from source code using McCabe's IQ tool. Nevertheless, not all faults can be explained by code metrics [15]. As discussed earlier, social networks [41] have an impact on software faults too. Although there may be other metrics that could improve MDP repository, currently available data points have been used many times in the literature demonstrating the robustness of fault prediction in the MDP projects [36, 30, 20, 17, 8, 38, 46, 50, 49, 21, 23, 24, 22, 32, 33]. Therefore, we believe that our experiments and results from MDP data sets are relevant for the software fault prediction community.

Considering external validity, MDP projects come from NASA's Space Shuttle program. It is entirely possible that NASA's verification and validation practices are significantly different from other software development organizations. While this is a possible source of bias, we would like to note that projects included in the MDP repository do not follow the same life-cycle activities, they come from several software development organizations and fall under varying criticality regimes.

With respect to construct validity, cost ratios in our experiments, which vary from  $\frac{1}{75}$  to 75 might not include all meaningful cost differentials. Different projects may have their own cost ranges of interests. Furthermore, cost evolves together with a software project's development process. Boehm and Papaccio observe that to fix a fault earlier in the lifecycle is much cheaper than later by a factor of 50-200 [4]. However, we do not think this will affect our conclusions since different costs only results in different points in cost-ignorant models.

The selection of classifiers is another possible source of bias. We cannot exclude the possibility that a classifier not studied here could show significantly better performance. Nevertheless, based on our experience, we believe that the chance of such a classification algorithm being in existence is rather low.

# 4. RELATED WORK

A large number of fault prediction modeling techniques have been proposed and applied to software fault prediction. Many of these techniques are relatively straightforward transplants from the fields of data mining and machine learning. Some of them, for example, logistic regression [3], aim to use domain-specific knowledge to establish the input (software metrics) output (software faults) relationship. Some techniques, such as classification trees [17, 6], neural networks [5], and genetic algorithms [25], try to examine the available large-size data sets to recognize patterns and form generalizations. Some utilize one single model to predict faults; others are based on ensemble learning and build a collection of models from a single training data set [32, 6]. Regression analysis (linear or logistic) [39, 40, 41] has the advantage that it can be used by itself but also in combinations with other algorithms, for example, classification trees, to form regression tree algorithm.

A decision tree algorithm, for example C4.5, is one of the most well studied classifiers which can depict the structure of software metrics. C4.5 uses a divide and conquer mechanism to build a decision tree from training set. After building and pruning the decision tree is fitted to the training data set. Models from decision trees are easy to interpret and, therefore, popular in practice when a fault prediction model needs explanation. Khoshgoftaar *et al.* 

used C4.5 to identify faulty modules and compared it with other algorithms [29] NaiveBayes (nb), as its name suggests, "naively" assumes independence between different prediction variables. This assumption is considered overly simplistic in real life application scenarios. However, in software engineering data sets, it's performance is surprisingly good [36]. Naive Bayes classifiers have been used extensively in fault prediction, for example in [36, 21, 20].

Random Forest is a decision tree based classifier. As implied from its name, it builds a "forest" of decision trees. In empirical studies, Random forest usually is one of the best classifiers in software engineering domain [17, 21, 20]. Bagging stands for bootstrap aggregating. It relies on an ensemble of different models. The training data is resampled from the original data set. Bagging typically performs better than any single method models and almost never significantly worse. It has shown to have good performance in software engineering experiments [21, 20]. Boosting combines multiple models by explicitly seeking models that complement one another. First, it is similar to bagging in using voting for classification or averaging for numeric prediction. Like bagging, boosting combines the models of the same type. However, boosting is iterative. "Whereas in bagging individual models are built separately, in boosting each new model is influenced by the performance of those built previously. Boosting encourages new models to become experts for instances handled incorrectly by earlier ones" [48]. Random forest, bagging and boosting develop an ensemble of base models and use them in combination. In our experiments, they demonstrate consistent performance in software fault prediction [21, 20].

Another way to improve the performance of fault prediction models is to use feature subset selection (FSS). FSS selects useful attributes or features and eliminate irrelevant or noisy features before learning process starts. Principal Component Analysis (PCA) is a classical method to cope with multicollinearity among attributes. PCA transforms a set of attributes (metrics, features) into their uncorrelated linear combinations. PCA selected nine major components from 38 software metrics on open source Apache 1.3 and 2.0 projects [10].

Ostrand and Weyuker define the cost of FP and FN as type I and type II misclassification cost [43]. They argue that in software fault prediction type II misclassification is likely more serious than type I misclassification. Therefore, attention should be put on higher  $cost\_ratio$  (  $=\frac{typeII}{typeI}$ ), which supports the similar trend in our experiments.

Cost factors have been considered in test case selection for regression testing too [13, 14]. Elbaum *et al.* [13, 14] incorporated different costs of test cases into software regression testing. They report that incorporating costs into testing can improve test suites' overall rate of fault detection. Further, the effectiveness is substantially improved, measured by the weighted average of the percentage of faults detected over the life of the test case suite (AFPD) [13, 14]. Although our result indicate that incorporating cost factors into fault modeling does not improve the overall performance of classification models, this does not mean that our experiments contradict theirs. The two studies have different goals (test case suites vs. fault prediction models) and utilize different success measures (APFD vs. ROC).

As mentioned earlier, misclassification cost has been used in the fault prediction literature but primarily for model evaluation. Cost curves [12, 20], a graphical technique for visualizing a software

fault prediction model over the full range of possible misclassification costs, has demonstrated its utility in software fault prediction modeling [23]. Cost curves evaluate software fault prediction models which are built assuming the uniform costs of misclassification, but project-specific costs can be incorporated into model evaluation.

#### 5. CONCLUSION

Software fault prediction models offer tangible advantages for optimizing project's V&V activities by uncovering modules in which software faults are most likely to hide. From the methodological perspective, these are binary classification models. Typical proportion of modules which are likely to contain faults is rather small. This makes automated binary classification problem of detecting faulty modules more difficult.

In this paper, we analyzed the possible advantages of cost sensitive software fault prediction modeling. Cost sensitive modeling assigns different cost factors to overlooking a faulty module and falsely tagging a fault free module as fault prone. By minimizing the overall cost of misclassification, rather than the number of misclassified modules, we expect to develop better classifiers.

We analyzed the impact of eleven different misclassification costs to software fault prediction modeling, using the projects from the NASA MDP repository. Cost-sensitive modeling does not improve the overall performance of classification models. Nevertheless, explicit information about misclassification cost makes it easier for software managers to select the most appropriate model for their specific project environment. The alternative to cost-sensitive modeling is to determine the most appropriate threshold in a set of models developed in absence of cost information, which we believe to be more challenging. Our experiments further indicate that in projects where the exact misclassification cost is unknown, a likely scenario in practice, cost sensitive models with similar misclassification cost ratios are likely to exhibit performance which is not significantly different.

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